

**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

2128

**SEARCHED**

Class	Subclass	Date	Examiner
703	2 UPDT	2/20/2006	AS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated East Search	2/20/2006	AS
Perfromed IEEE Seach (attached)	2/20/2006	AS
Consulted SPE	2/16/2006	AS